

Search Notes

Application/Control No.

10/054,734

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

IKEDA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	418	8/10/2004	HN
	419		
	420		
	432.1		
	433		
	561		
	404.1		
	456.1		
	456.2		
	422.1		
Updated	search	6/3/2005	HN
Updated	search	7/26/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	418	7/26/2006	HN
	419		
	420		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	8/10/2004	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	6/3/2005	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	7/26/2006	HN
See interference search printout.	7/26/2006	HN